Solderability

Vibration

Temperature Cycling



Series -RoHS Compliant (Pb-free) Low Current 3.3V 4 Pad 5mm x 7mm Ceramic SMD LVCMOS Oscillator

Frequency Tolerance/Stability ±20ppm over -40°C to +85°C

Duty Cycle -50 ±5(%)

EB13C3 K 2 H -44.730M

L Nominal Frequency 44.730MHz

Logic Control / Additional Output Tri-State (High Impedance)

Nominal Frequency	44.730MHz
• •	
Frequency Tolerance/Stability	±20ppm over -40°C to +85°C (Inclusive of all conditions: Calibration Tolerance at 25°C, Frequency Stability over the Operating Temperature Range, Supply Voltage Change, Ouput Load Change, First Year Aging at 25°C, Shock, and Vibration)
Supply Voltage	3.3Vdc ±10%
Input Current	12mA Maximum
Output Voltage Logic High (Voh)	90% of Vdd Minimum
Input Current Logic High (Ioh)	-8mA
Output Voltage Logic Low (Vol)	10% of Vdd Maximum
Input Current Logic Low (IoI)	+8mA
Rise/Fall Time	4nSec Maximum (Measured at 20% to 80% of waveform)
Duty Cycle	50 ±5(%) (Measured at 50% of waveform)
Load Drive Capability	15pF Maximum
Output Logic Type	CMOS
Logic Control / Additional Output	Tri-State (High Impedance)
Tri-State Input Voltage (Vih and Vil)	90% of Vdd Minimum or No Connect to Enable Output, 10% of Vdd Maximum to Disable Output (High Impedance)
Standby Current	10µA Maximum (Disabled Output: High Impedance)
One Sigma Clock Period Jitter	25pSec Maximum
Start Up Time	10mSec Maximum
Storage Temperature Range	-55°C to +125°C

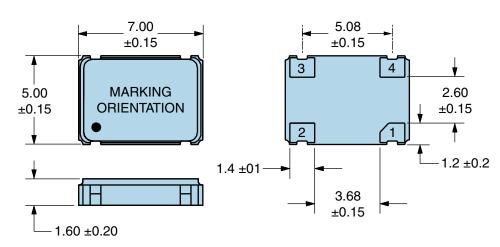
ENVIRONMENTAL & MECHANICAL SPECIFICATIONS		
Fine Leak Test	MIL-STD-883, Method 1014, Condition A	
Gross Leak Test	MIL-STD-883, Method 1014, Condition C	
Mechanical Shock	MIL-STD-202, Method 213, Condition C	
Resistance to Soldering Heat	MIL-STD-202, Method 210	
Resistance to Solvents	MIL-STD-202, Method 215	

MIL-STD-883, Method 2003

MIL-STD-883, Method 1010

MIL-STD-883, Method 2007, Condition A

MECHANICAL DIMENSIONS (all dimensions in millimeters)



PIN	CONNECTION
1	Tri-State
2	Ground
3	Output
4	Supply Voltage
LINE	MARKING
LINE 1	MARKING ECLIPTEK

Suggested Solder Pad Layout

All Dimensions in Millimeters



All Tolerances are ±0.1





OUTPUT WAVEFORM & TIMING DIAGRAM



Test Circuit for CMOS Output



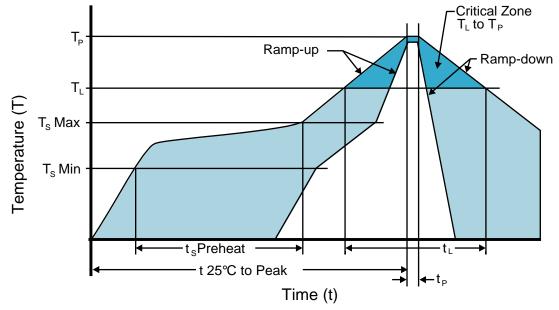
Note 1: An external 0.1μ F low frequency tantalum bypass capacitor in parallel with a 0.01μ F high frequency ceramic bypass capacitor close to the package ground and V_{DD} pin is required.

Note 2: A low capacitance (<12pF), 10X attenuation factor, high impedance (>10Mohms), and high bandwidth (>300MHz) passive probe is recommended.

Note 3: Capacitance value \dot{C}_L includes sum of all probe and fixture capacitance.



Recommended Solder Reflow Methods



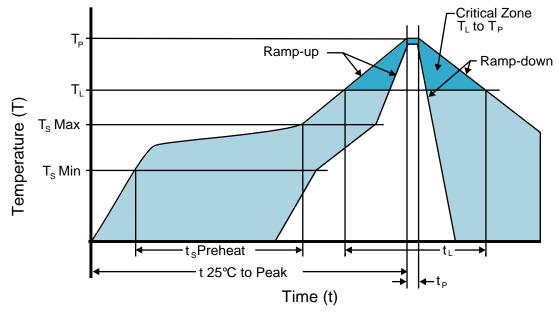
High Temperature Infrared/Convection

3 1		
T _s MAX to T _L (Ramp-up Rate)	3°C/second Maximum	
Preheat		
- Temperature Minimum (T _s MIN)	150°C	
 Temperature Typical (T_s TYP) 	175°C	
 Temperature Maximum (T_s MAX) 	200°C	
- Time (t _s MIN)	60 - 180 Seconds	
Ramp-up Rate (T⊾ to T _P)	3°C/second Maximum	
Time Maintained Above:		
- Temperature (T∟)	217°C	
- Time (t∟)	60 - 150 Seconds	
Peak Temperature (T _P)	260°C Maximum for 10 Seconds Maximum	
Target Peak Temperature (T _P Target)	250°C +0/-5°C	
Time within 5°C of actual peak (t _p)	20 - 40 seconds	
Ramp-down Rate	6°C/second Maximum	
Time 25°C to Peak Temperature (t)	8 minutes Maximum	
Moisture Sensitivity Level	Level 1	
Additional Notes	Temperatures shown are applied to body of device.	



Recommended Solder Reflow Methods

EB13C3K2H-44.730M



Low Temperature Infrared/Convection 240°C

•	
T _s MAX to T _L (Ramp-up Rate)	5°C/second Maximum
Preheat	
 Temperature Minimum (T_s MIN) 	N/A
 Temperature Typical (T_s TYP) 	150°C
 Temperature Maximum (T_s MAX) 	N/A
- Time (t _s MIN)	60 - 120 Seconds
Ramp-up Rate (T⊾ to T _P)	5°C/second Maximum
Time Maintained Above:	
- Temperature (T∟)	150°C
- Time (t∟)	200 Seconds Maximum
Peak Temperature (T _P)	240°C Maximum
Target Peak Temperature (T _P Target)	240°C Maximum 1 Time / 230°C Maximum 2 Times
Time within 5°C of actual peak (t _p)	10 seconds Maximum 2 Times / 80 seconds Maximum 1 Time
Ramp-down Rate	5°C/second Maximum
Time 25°C to Peak Temperature (t)	N/A
Moisture Sensitivity Level	Level 1
Additional Notes	Temperatures shown are applied to body of device.

Low Temperature Manual Soldering

185°C Maximum for 10 seconds Maximum, 2 times Maximum. (Temperatures shown are applied to body of device.)

High Temperature Manual Soldering

260°C Maximum for 5 seconds Maximum, 2 times Maximum. (Temperatures shown are applied to body of device.)